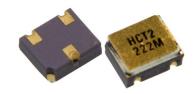
## N-Channel Enhancement Mode MOS Transistor



## HCT7000M, HCT70000MTX, HCT7000MTXV

### Features:

- 200 mA I<sub>D</sub>
- Ultra small surface mount package
- $R_{DS(ON)} < 5\Omega$
- Pin-out compatible with most SOT23 MOSFETS



## **Description:**

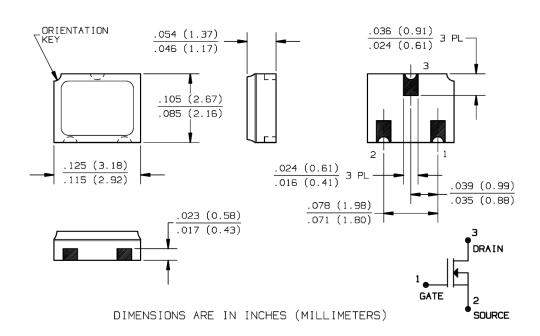
The HCT7000M is a high performance enhancement mode N-channel MOS transistor chip packaged in the ultra small 3 pin ceramic LCC package. Electrical characteristics are similar to those of the JEDEC 2N7000. The pin-out and footprint matches that of most enhancement mode MOS transistors built in SOT23 plastic packages.

TX and TXV devices are processed to OPTEK's military screening program patterned after MIL-PRF-19500. TX products receive a  $V_{GS}$  HTRB at 24 V for 48 hrs. at 150° C and a  $V_{DS}$  HTRB at 48 V for 260 hrs.at 150° C.

## **Applications:**

- Switching applications: small servo motor control, power MOSFET gate drives
- Relay Drivers
- High Speed Line Drivers
- Power Supplies

Part Number	Sensor Type	V <sub>DSS</sub> Min	V <sub>GS(TH)</sub> Min/ Max	I <sub>D(ON)</sub> (mA) Min	G <sub>fs</sub> (ms) Min	t <sub>(ON)</sub> / t <sub>(OFF)</sub> (ns) Max	Package
HCT7000M	N-Channel						
HCT7000MTX	Enhanced	60	0.8 / 3.0	75	100	10 / 10	3-pin Ceramic
HCT7000MTXV	MOSFET						



# N-Channel Enhancement Mode MOS Transistor



# HCT7000M, HCT70000MTX, HCT7000MTXV

## **Performance**

Absolute Maximum Ratings				
Drain Source Voltage	60V			
Gate-Source Voltage	±40 V			
Drain Current	200 mA			
Power Dissipation (T <sub>A</sub> = 25° C)	300 mW			
Power Dissipation (T <sub>S</sub> <sup>(1)</sup> = 25° C)	600 mW <sup>(2)</sup>			
Operating and Storage Temperature	-55° C to 150° C			
Thermal Resistance R <sub>ØJC</sub>	100° C/W			
Thermal Resistance R <sub>ØJA</sub>	583° C/W			

## Electrical Characteristics (T<sub>A</sub> = 25° C unless otherwise noted)

SYMBOL	PARAMETER	MIN	МАХ	UNITS	TEST CONDITIONS	
V <sub>DSS</sub>	Drain Source Voltage	60		V	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 10 μa	
V <sub>GS(TH)</sub>	Gate Threshold Voltage	.8	3.0	V	$V_{DS} = V_{GS}$ , $I_D = 1$ mA	
I <sub>GSS</sub>	Gate Leakage		±10	nA	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = ±15 V	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current		1	μΑ	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 48 V	
I <sub>D(ON)</sub>	(ON) On-Site Drain Current			mA	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 4.5 V	
R <sub>DS(ON)</sub>	Drain Source on-Resistance		5	Ω	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.5 A	
V <sub>DS(ON)</sub>	Drain Source on-Voltage		2.5	V	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.5 A	
G <sub>fs</sub>	Forward Transconductance			mS	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 0.2 A	
C <sub>iss</sub>	Input Capacitance		60	pF	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1MHz	
C <sub>oss</sub>	Output Capacitance		25	pF		
C <sub>rss</sub>	Reverse Transfer Capacitance		5	pF	-	
t <sub>(on)</sub>	Turn-on Time		10	ns		
t <sub>(off)</sub>	Turn-off Time		10	ns	$ V_{DD} = 15 \text{ V}, I_D = 0.5 \text{ A}, V_{gen} = 10 \text{ V}, R_g = 25 \Omega$	

#### Note:

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<sup>1)</sup>  $T_S$  = Substrate temperature that the chip carrier is mounted on.

<sup>2)</sup> This rating is provided as an aid to designers. It is dependent upon mounting material and methods and is not measurable as an outgoing test.